

10/590017
1AP9 Rec'd PCT/PTO 17 AUG 2006

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IN THE U.S. PATENT AND TRADEMARK OFFICE

August 17, 2006

Applicant : Masakazu SUEYASU
For : APPARATUS FOR COOLING AND CLEANING
EMISSION GAS GENERATED FROM REFLOW FURNACE

PCT International Application No.: PCT/JP2005/003219

PCT International Filing Date: February 14, 2005

U.S. Application No.

(if known, see 37 CFR 1.5): Unknown

Atty. Docket No.: 4900.P0057US

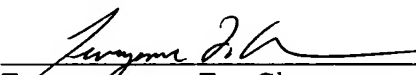
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INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. These references are listed on the International Search Report. Further comment at this point in time should not be necessary.

Respectfully submitted,


Terryence F. Chapman

TFC/smd

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Encl: International Search Report
Form PTO-1449 and one copy of each listed reference

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INFORMATION
DISCLOSURE
CITATION

Applicant: Masakazu SUEYASU

Ser.No.: Unknown

Conf. No.: Unknown

Group: Unknown

Filed: Unknown

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Date: August 17, 2006

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U.S. PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant |
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FOREIGN PATENT DOCUMENTS

| Examiner Initials* | Cite No. | Country Code - Document Number - Kind Code | Publication Date MM-DD-YYYY | Name of Patentee or Applicant | Trans. |
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NON PATENT LITERATURE DOCUMENTS

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